

CBCS SCHEME

USN

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20ELD14

First Semester M.Tech. Degree Examination, July/August 2022 Digital Circuits and Logic Design

Time: 3 hrs.

Max. Marks: 100

Note: Answer any FIVE full questions, choosing ONE full question from each module.

Module-1

- 1 a. Define threshold element, threshold function, positive and negative unate functions. (10 Marks)
- b. Identify minimal true and maximal false vertices for the function :
 $f(x_1, x_2, x_3, x_4) = \Sigma m(2, 3, 6, 7, 15)$
Find the weight threshold vector for the same. (10 Marks)

OR

- 2 a. Implement the following Boolean function using single threshold element.
 $f(x_1, x_2, x_3) = \Sigma m(0, 2, 4, 6, 7)$. (10 Marks)
- b. Implement full adder using two threshold elements. (10 Marks)

Module-2

- 3 a. Using path sensitization method, generate complete test set to detect line 2 s-a-0 fault considering two single paths and one double path for the circuit shown in Fig.Q3(a).

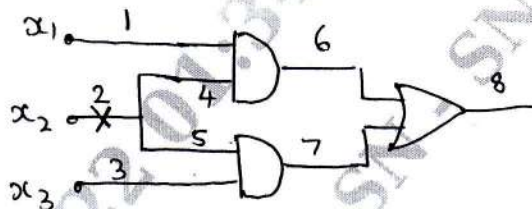


Fig.Q3(a)

- b. Using K-map method, find minimal set of test for multiple faults for two level AND-OR realization of the function $f(a, b, c, d) = ad' + bc' + a'b + ab'c$. (10 Marks)

OR

- 4 a. What do you mean by critical and subcritical errors? Summarize three errors for AND, OR, NAND, NOR, majority and modulo 2 gates. (10 Marks)
- b. For the circuit shown in Fig.Q4(b) show that faults e s-a-0 and h s-a-1 are undetectable. Generate complete test sets for faults e s-a-1 and h s-a-0.

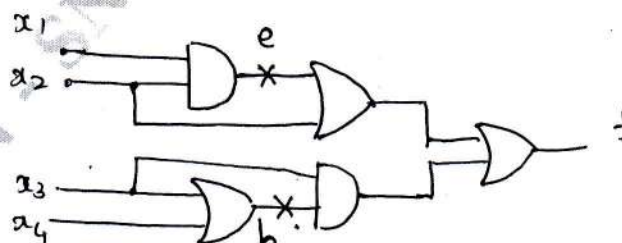


Fig.Q4(b)

(10 Marks)

Module-3

- 5 a. For the machine shown in Table Q5(a), find equivalence partition and show a standard form of corresponding reduced machine. Find minimum length sequence that distinguishes state S0 from S4.

| PS | NS, Z | |
|----------------|--------------------|--------------------|
| | x = 0 | x = 1 |
| S ₀ | S ₄ , 0 | S ₃ , 1 |
| S ₁ | S ₅ , 0 | S ₃ , 0 |
| S ₂ | S ₄ , 0 | S ₁ , 1 |
| S ₃ | S ₅ , 0 | S ₁ , 0 |
| S ₄ | S ₂ , 0 | S ₅ , 1 |
| S ₅ | S ₁ , 0 | S ₂ , 0 |

Table Q5(a)

(10 Marks)

- b. For the Machine shown in Table Q5(b), draw merger table and reduce the machine.

| PS | NS, Z | | | |
|----|-------|-----|-----|-----|
| | 00 | 01 | 11 | 10 |
| A | B,0 | C,0 | B,1 | A,0 |
| B | E,0 | C,0 | B,1 | D,1 |
| C | A,0 | B,0 | C,1 | D,1 |
| D | C,0 | D,0 | A,1 | B,0 |
| E | C,0 | C,0 | C,1 | E,0 |

Table Q5(b)

(10 Marks)

OR

- 6 a. For the incompletely specified machine shown in Table Q6(a), find minimum state reduced machine containing original one.

| PS | NS, Z | | | |
|----|-------|------|------|------|
| | 00 | 01 | 10 | 11 |
| A | 0,0 | -, - | A,0 | -, - |
| B | -, - | E,0 | B,0 | D,1 |
| C | D,0 | B,1 | -, - | -, - |
| D | C,0 | A,1 | E,0 | -, - |
| E | B,0 | -, - | A,0 | E,1 |

Table Q6(a)

(10 Marks)

- b. By taking direct sum of M₁ and M₂ show that state A of M₁ is equivalent to state H of M₂. Prove that machine M₁ is contained in machine M₂.

M₁

| PS | NS, Z | |
|----|-------|-------|
| | x = 0 | x = 1 |
| A | B, 0 | C, 1 |
| B | D, 1 | C, 0 |
| C | A, 1 | C, 0 |
| D | B, 1 | C, 0 |

M₂

| PS | NS, Z | |
|----|-------|-------|
| | x = 0 | x = 1 |
| E | H, 1 | E, 0 |
| F | F, 1 | E, 0 |
| G | E, 0 | G, 1 |
| H | F, 0 | E, 1 |

(10 Marks)

Module-4

- 7 a. Define : closed partition, input consistent partition, output consistent partition. (10 Marks)
b. Explain serial decomposition and parallel decomposition of finite state machines. (10 Marks)

OR

- 8 a. Find the input consistent and output consistent partitions for the machine shown in Table Q8(a). Decompose the machine into three series components such that output logic is minimized.

Given :

$$\pi_1 = \{ \overline{ABEF}, \overline{CDGH} \}.$$

| PS | NS | | Z | |
|----|-----|-----|-----|-----|
| | x=0 | x=1 | x=0 | x=1 |
| A | D | C | 0 | 0 |
| B | C | D | 0 | 1 |
| C | E | F | 0 | 0 |
| D | F | F | 0 | 1 |
| E | G | H | 0 | 0 |
| F | H | G | 0 | 1 |
| G | B | A | 0 | 0 |
| H | A | B | 0 | 1 |

Table Q8(a)

(10 Marks)

- b. Closed partitions for a FSM are shown below, construct π - lattice for the same.

$$\pi(I) = \{ \overline{A, B, C, D, E, F, G} \}$$

$$\pi_1 = \{ \overline{ACDE}, \overline{BFG} \}$$

$$\pi_2 = \{ \overline{AG}, \overline{BE}, \overline{CDF} \}$$

$$\pi_3 = \{ \overline{ABEG}, \overline{CDF} \}$$

$$\pi_4 = \{ \overline{AEF}, \overline{BCDG} \}$$

$$\pi_5 = \{ \overline{AE}, \overline{BG}, \overline{CD}, \overline{F} \}$$

$$\pi_6 = \{ \overline{A}, \overline{B}, \overline{CD}, \overline{E}, \overline{F}, \overline{G} \}$$

$$\pi(0) = \{ \overline{A}, \overline{B}, \overline{C}, \overline{D}, \overline{E}, \overline{F}, \overline{G} \}$$

(10 Marks)

Module-5

- 9 a. Find the shortest preset distinguishing sequence for the FSM shown in Table Q9(a).

| PS | NS, Z | |
|----|-------|-----|
| | x=0 | x=1 |
| A | C, 1 | D |
| B | A, 1 | C |
| C | D, 2 | B |
| D | C, 2 | A |

Table Q9(a)

(10 Marks)

- b. Show the testing table and testing graph for machine shown in TableQ9(b). Add to the machine one output terminal so that the sequence 11 will be a distinguishing sequence.

| PS | NS, Z | |
|----|-------|------|
| | x=0 | x=1 |
| A | D, 0 | B, 0 |
| B | C, 0 | B, 0 |
| C | D, 1 | C, 1 |
| D | E, 1 | E, 1 |
| E | E, 1 | A, 1 |

Table Q9(b)

(10 Marks)

OR

- 10 a. Describe Homing experiments and distinguishing experiments. (10 Marks)
 b. The following experiment has been proposed as a fault detection experiment for machine shown in Table Q10(b). When started in state A and under the assumption that number of states will not increase as a result of malfunction. Prove that it is a proper fault detection experiment.

Input 0 0 1 0 0 1 0 1 0 1 1 0 0 0 1 0 0
 Output 2 2 2 0 1 0 2 2 0 0 2 1 2 1 1 2 2

| PS | NS, Z | |
|----|-------|------|
| | x=0 | x=1 |
| A | A, 2 | B, 2 |
| B | C, 0 | A, 1 |
| C | D, 1 | E, 0 |
| D | E, 2 | A, 0 |
| E | B, 1 | C, 2 |

Table Q10(b)

(10 Marks)
